


<b>Search Notes</b> 	<b>Application/Control No.</b> 10759642	<b>Applicant(s)/Patent Under Reexamination</b> ERIC YEH ET AL.
	<b>Examiner</b> PIERRE-LOUIS DESIR	<b>Art Unit</b> 2617

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SEARCH NOTES		
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INTERFERENCE SEARCH			
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